

### Features

- 30A, 1200V
- Latch Free Operation
- Typical Fall Time - 580ns
- High Input Impedance
- Low Conduction Loss

### Description

The HGTG30N120D2 is a MOS gated high voltage switching device combining the best features of MOSFETs and bipolar transistors. The device has the high input impedance of a MOSFET and the low on-state conduction loss of a bipolar transistor. The much lower on-state voltage drop varies only moderately between +25°C and +150°C.

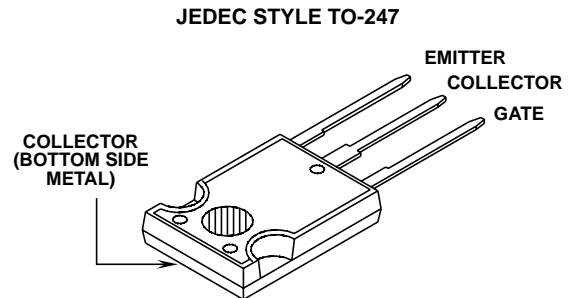
The IGBTs are ideal for many high voltage switching applications operating at moderate frequencies where low conduction losses are essential, such as: AC and DC motor controls, power supplies and drivers for solenoids, relays and contactors.

#### PACKAGING AVAILABILITY

PART NUMBER	PACKAGE	BRAND
HGTG30N120D2	TO-247	G30N120D2

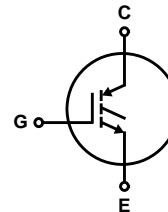
Formerly Developmental Type TA49010

### Package



### Terminal Diagram

#### N-CHANNEL ENHANCEMENT MODE



### Absolute Maximum Ratings $T_C = +25^\circ\text{C}$ , Unless Otherwise Specified

	HGTG30N120D2	UNITS
Collector-Emitter Voltage	1200	V
Collector-Gate Voltage, $R_{GE} = 1\text{M}\Omega$	1200	V
Collector Current Continuous at $T_C = +25^\circ\text{C}$	50	A
at $V_{GE} = 15\text{V}$ at $T_C = +90^\circ\text{C}$	30	A
Collector Current Pulsed (Note 1)	200	A
Gate-Emitter Voltage Continuous	$\pm 20$	V
Gate-Emitter Voltage Pulsed	$\pm 30$	V
Switching Safe Operating Area at $T_J = +150^\circ\text{C}$	200A at 0.8 $BV_{CES}$	-
Power Dissipation Total at $T_C = +25^\circ\text{C}$	208	W
Power Dissipation Total Derating $T_C > +25^\circ\text{C}$	1.67	W/ $^\circ\text{C}$
Operating and Storage Junction Temperature Range	-55 to +150	$^\circ\text{C}$
Maximum Lead Temperature for Soldering	260	$^\circ\text{C}$
Short Circuit Withstand Time (Note 2) at $V_{GE} = 15\text{V}$	6	$\mu\text{S}$
at $V_{GE} = 10\text{V}$	15	$\mu\text{S}$

#### NOTES:

1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2.  $V_{CE(PEAK)} = 720\text{V}$ ,  $T_C = +125^\circ\text{C}$ ,  $R_{GE} = 25\Omega$ .

#### HARRIS SEMICONDUCTOR IGBT PRODUCT IS COVERED BY ONE OR MORE OF THE FOLLOWING U.S. PATENTS:

4,364,073	4,417,385	4,430,792	4,443,931	4,466,176	4,516,143	4,532,534	4,567,641
4,587,713	4,598,461	4,605,948	4,618,872	4,620,211	4,631,564	4,639,754	4,639,762
4,641,162	4,644,637	4,682,195	4,684,413	4,694,313	4,717,679	4,743,952	4,783,690
4,794,432	4,801,986	4,803,533	4,809,045	4,809,047	4,810,665	4,823,176	4,837,606
4,860,080	4,883,767	4,888,627	4,890,143	4,901,127	4,904,609	4,933,740	4,963,951
4,969,027							

# Specifications HGTG30N120D2

## Electrical Specifications $T_C = +25^\circ\text{C}$ , Unless Otherwise Specified

PARAMETERS	SYMBOL	TEST CONDITIONS	LIMITS			UNITS		
			MIN	TYP	MAX			
Collector-Emitter Breakdown Voltage	$BV_{CES}$	$I_C = 250\mu\text{A}$ , $V_{GE} = 0\text{V}$	1200	-	-	V		
Zero Gate Voltage Collector Current	$I_{CES}$	$V_{CE} = BV_{CES}$ , $T_C = +25^\circ\text{C}$	-	-	1.0	mA		
		$V_{CE} = 0.8 BV_{CES}$ , $T_C = +125^\circ\text{C}$	-	-	4.0	mA		
Collector-Emitter Saturation Voltage	$V_{CE(SAT)}$	$I_C = I_{C90}$ , $V_{GE} = 15\text{V}$	$T_C = +25^\circ\text{C}$	-	3.0	3.5	V	
			$T_C = +125^\circ\text{C}$	-	3.2	3.5	V	
		$I_C = I_{C90}$ , $V_{GE} = 10\text{V}$	$T_C = +25^\circ\text{C}$	-	3.2	3.8	V	
			$T_C = +125^\circ\text{C}$	-	3.4	3.8	V	
Gate-Emitter Threshold Voltage	$V_{GE(TH)}$	$V_{GE} = V_{CE}$ , $I_C = 1\text{mA}$ , $T_C = +25^\circ\text{C}$	3.0	4.5	6.0	V		
Gate-Emitter Leakage Current	$I_{GES}$	$V_{GE} = \pm 20\text{V}$	-	-	$\pm 500$	nA		
Gate-Emitter Plateau Voltage	$V_{GEP}$	$I_C = I_{C90}$ , $V_{CE} = 0.5 BV_{CES}$	-	7.3	-	V		
On-State Gate Charge	$Q_{G(ON)}$	$I_C = I_{C90}$ , $V_{CE} = 0.5 BV_{CES}$	$V_{GE} = 15\text{V}$	-	185	240	nC	
			$V_{GE} = 20\text{V}$	-	240	315	nC	
Current Turn-On Delay Time	$t_{D(ON)I}$	$L = 50\mu\text{H}$ , $I_C = I_{C90}$ , $R_G = 25\Omega$ , $V_{GE} = 15\text{V}$ , $T_J = +125^\circ\text{C}$ , $V_{CE} = 0.8 BV_{CES}$	-	100	-	ns		
Current Rise Time	$t_{RI}$		-	150	-	ns		
Current Turn-Off Delay Time	$t_{D(OFF)I}$		-	760	990	ns		
Current Fall Time	$t_{FI}$		-	580	750	ns		
Turn-Off Energy (Note 1)	$W_{OFF}$		-	8.4	-	mJ		
Current Turn-On Delay Time	$t_{D(ON)I}$	$L = 50\mu\text{H}$ , $I_C = I_{C90}$ , $R_G = 25\Omega$ , $V_{GE} = 10\text{V}$ , $T_J = +125^\circ\text{C}$ , $V_{CE} = 0.8 BV_{CES}$	-	100	-	ns		
			Current Rise Time	$t_{RI}$	-	150	-	ns
			Current Turn-Off Delay Time	$t_{D(OFF)I}$	-	610	790	ns
			Current Fall Time	$t_{FI}$	-	580	750	ns
			Turn-Off Energy (Note 1)	$W_{OFF}$	-	8.4	-	mJ
Thermal Resistance Junction-to-Case	$R_{\theta JC}$		-	0.5	0.6	$^\circ\text{C/W}$		

NOTE: 1. Turn-Off Energy Loss ( $W_{OFF}$ ) is defined as the integral of the instantaneous power loss starting at the trailing edge of the input pulse and ending at the point where the collector current equals zero ( $I_{CE} = 0\text{A}$ ). The HGTG20N100D2 was tested per JEDEC standard No. 24-1 Method for Measurement of Power Device Turn-Off Switching Loss. This test method produces the true total Turn-Off Energy Loss.

## Typical Performance Curves

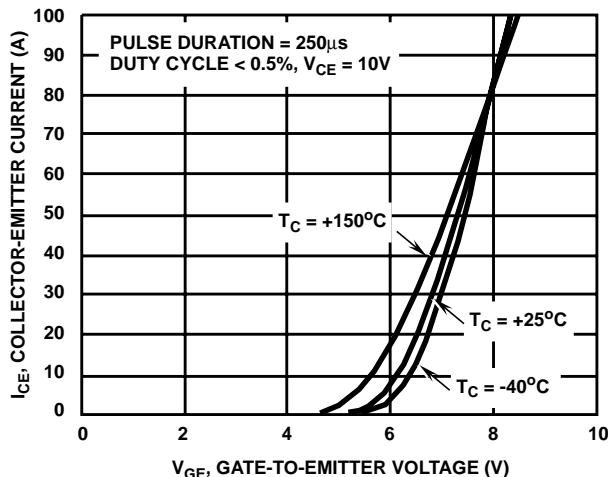


FIGURE 1. TRANSFER CHARACTERISTICS (TYPICAL)

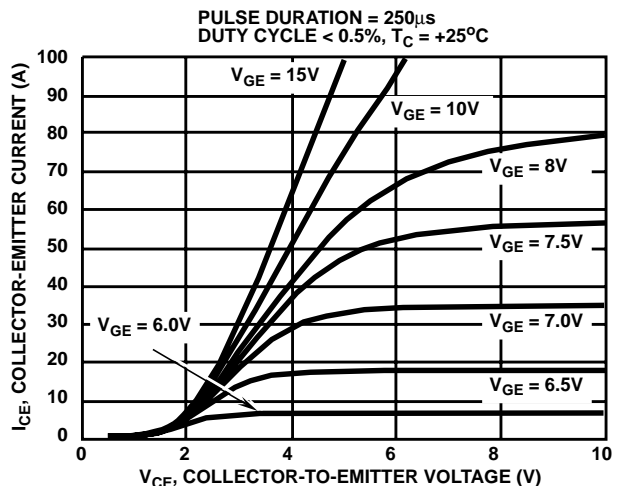


FIGURE 2. SATURATION CHARACTERISTICS (TYPICAL)

Typical Performance Curves (Continued)

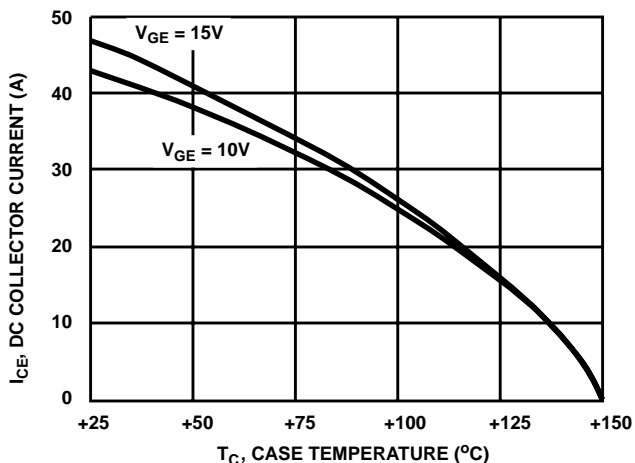


FIGURE 3. DC COLLECTOR CURRENT vs CASE TEMPERATURE

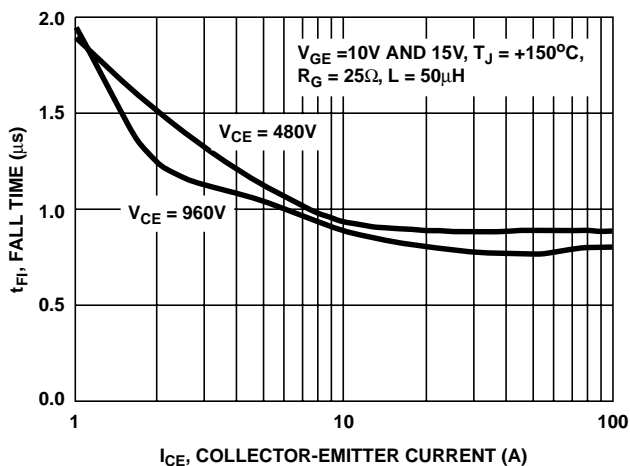


FIGURE 4. FALL TIME vs COLLECTOR-EMITTER CURRENT

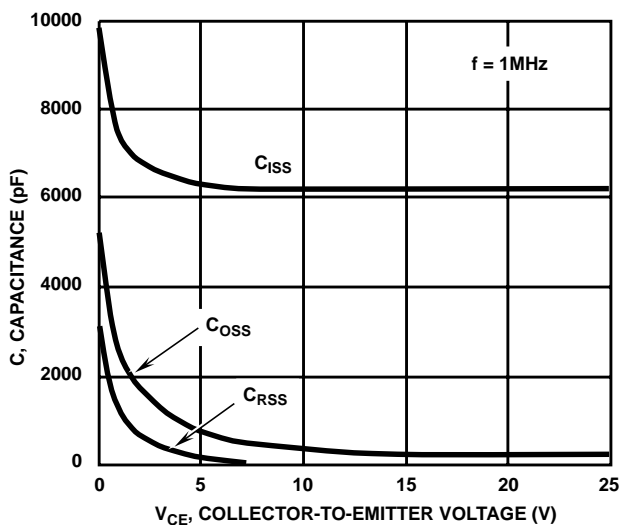


FIGURE 5. CAPACITANCE vs COLLECTOR-EMITTER VOLTAGE

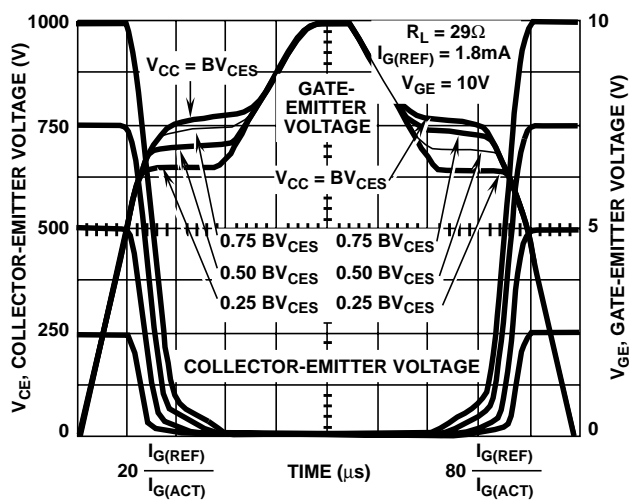


FIGURE 6. NORMALIZED SWITCHING WAVEFORMS AT CONSTANT GATE CURRENT (REFER TO APPLICATION NOTES AN7254 AND AN7260)

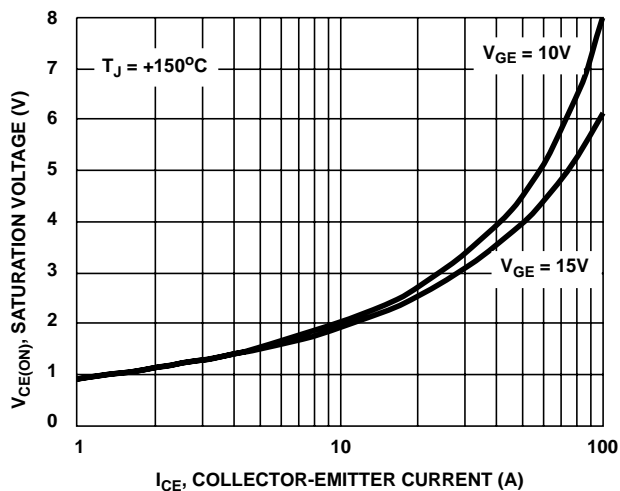


FIGURE 7. SATURATION VOLTAGE vs COLLECTOR-EMITTER CURRENT

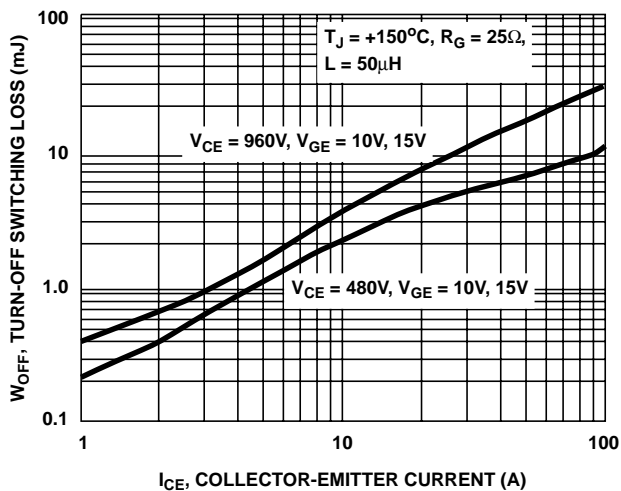


FIGURE 8. TURN-OFF SWITCHING LOSS vs COLLECTOR-EMITTER CURRENT

Typical Performance Curves (Continued)

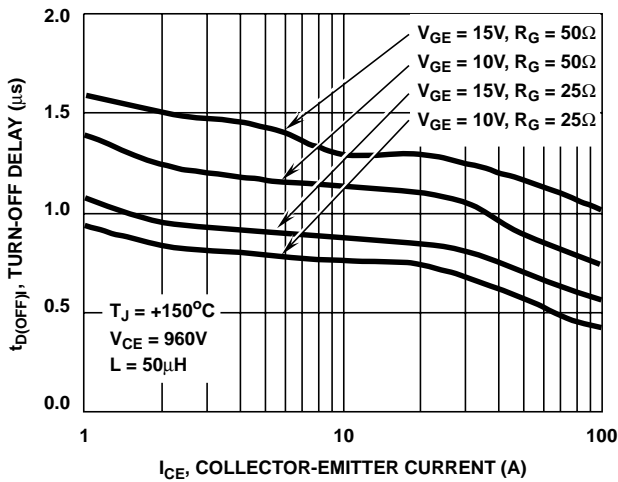
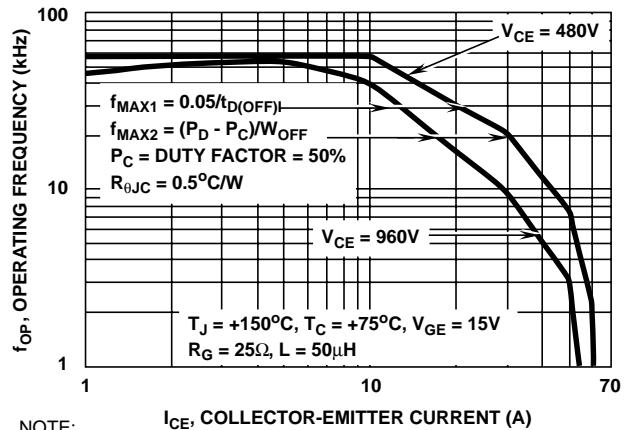


FIGURE 9. TURN-OFF DELAY vs COLLECTOR-EMITTER CURRENT



NOTE:  $f_{OP}$  = ALLOWABLE OPERATING FREQUENCY  
 $f_{MAX1} = 0.05/t_{D(OFF)}$   
 $f_{MAX2} = (P_D - P_C)/W_{OFF}$   
 $P_C$  = DUTY FACTOR = 50%  
 $R_{\theta JC} = 0.5^\circ C/W$

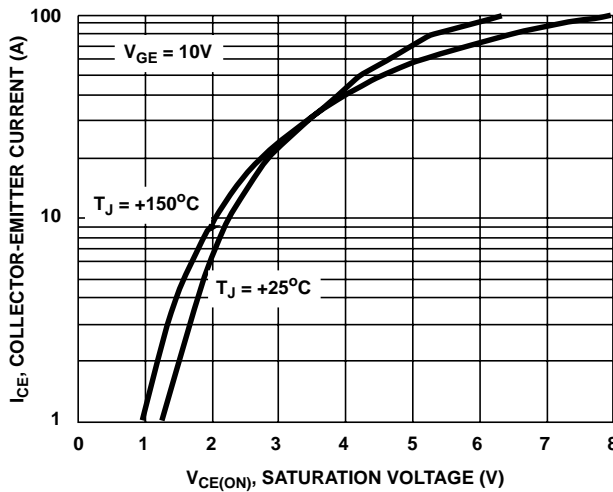


FIGURE 11. COLLECTOR-EMITTER SATURATION VOLTAGE

Test Circuit

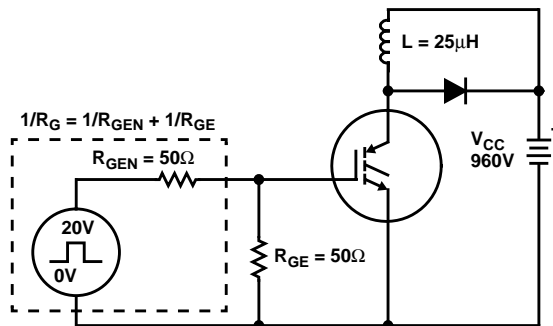


FIGURE 12. INDUCTIVE SWITCHING TEST CIRCUIT

## Operating Frequency Information

Operating frequency information for a typical device (Figure 10) is presented as a guide for estimating device performance for a specific application. Other typical frequency vs collector current ( $I_{CE}$ ) plots are possible using the information shown for a typical unit in Figures 7, 8 and 9. The operating frequency plot (Figure 10) of a typical device shows  $f_{MAX1}$  or  $f_{MAX2}$  whichever is smaller at each point. The information is based on measurements of a typical device and is bounded by the maximum rated junction temperature.

$f_{MAX1}$  is defined by  $f_{MAX1} = 0.05/t_{D(OFF)}$ .  $t_{D(OFF)}$  (the denominator) has been arbitrarily held to 10% of the on-state time for a 50% duty factor. Other definitions are possible.  $t_{D(OFF)}$  is defined as the time between the 90% point of the trailing edge of the input pulse and the point where the collector current falls to 90% of its maximum value. Device

turn-off delay can establish an additional frequency limiting condition for an application other than  $T_{JMAX}$ .  $t_{D(OFF)}$  is important when controlling output ripple under a lightly loaded condition.

$f_{MAX2}$  is defined by  $f_{MAX2} = (P_D - P_C)/W_{OFF}$ . The allowable dissipation ( $P_D$ ) is defined by  $P_D = (T_{JMAX} - T_C)/R_{\theta JC}$ . The sum of device switching and conduction losses must not exceed  $P_D$ . A 50% duty factor was used (Figure 10) and the conduction losses ( $P_C$ ) are approximated by  $P_C = (V_{CE} \cdot I_{CE})/2$ .  $W_{OFF}$  is defined as the integral of the instantaneous power loss starting at the trailing edge of the input pulse and ending at the point where the collector current equals zero ( $I_{CE} = 0A$ ).

The switching power loss (Figure 10) is defined as  $f_{MAX2} \cdot W_{OFF}$ . Turn-on switching losses are not included because they can be greatly influenced by external circuit conditions and components.

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